

ISO/TR 15969:2001-06 (E)

Surface chemical analysis - Depth profiling - Measurement of sputtered depth

Contents		Page
Foreword		iv
1	Scope	1
2	Terms and definitions	1
3	Abbreviated terms	2
4	Methods of determination of the sputtered depth	2
4.1	Crater depth measurement after sputter profiling	2
4.2	Comparison with sputter profiled samples having interfaces as depth markers	5
4.3	Typical applications and uncertainties of the different methods	9
Annex A Survey of typical applications and uncertainties of the different methods		10
Bibliography		11